

L Number	Hits	Search Text	DB	Time stamp
1	3	4761607.pn. or 4357540.pn. or 4503329.pn.	USPAT; US-PGPUB	2004/04/26 16:39
2	0	(4761607.pn. or 4357540.pn. or 4503329.pn.) and (until near3 failure)	USPAT; US-PGPUB	2004/04/26 16:19
3	1	(4761607.pn. or 4357540.pn. or 4503329.pn.) and failure\$2	USPAT; US-PGPUB	2004/04/26 16:06
4	0	(4761607.pn. or 4357540.pn. or 4503329.pn.) and (failure\$2 with induce\$2)	USPAT; US-PGPUB	2004/04/26 16:07
5	0	(4761607.pn. or 4357540.pn. or 4503329.pn.) and (failure\$2 with (induc\$5 or introduc\$5))	USPAT; US-PGPUB	2004/04/26 16:39
6	56	(inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))	USPAT; US-PGPUB	2004/04/26 17:18
7	15	(inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))	USPAT; US-PGPUB	2004/04/26 16:33
8	11	(inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:32
9	1	((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)) and ((scanning adj electron adj microscop\$5) or SEM)	USPAT; US-PGPUB	2004/04/26 16:11
11	0	5475695.pn. and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))	USPAT; US-PGPUB	2004/04/26 16:18
12	0	5475695.pn. and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:18
13	0	5475695.pn. and (failure\$2 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:31
14	0	5475695.pn. and (until near3 failure)	USPAT; US-PGPUB	2004/04/26 16:30
15	1	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (until near3 failure)	USPAT; US-PGPUB	2004/04/26 16:30
17	11	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:32
18	15	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))	USPAT; US-PGPUB	2004/04/26 16:32
19	15	((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))) not (5475695.pn. and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5)))	USPAT; US-PGPUB	2004/04/26 16:33
20	4	((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))) not ((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5))	USPAT; US-PGPUB	2004/04/26 16:33

16	43	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:37
21	0	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with induc\$5 with (maximum near3 rating))	USPAT; US-PGPUB	2004/04/26 16:38
22	0	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with (maximum near3 rating))	USPAT; US-PGPUB	2004/04/26 16:38
23	0	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and failure\$2 and (maximum near3 rating)	USPAT; US-PGPUB	2004/04/26 16:39
24	0	(4761607.pn. or 4357540.pn. or 4503329.pn.) and (failure\$2 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:39
25	0	(4761607.pn. or 4357540.pn. or 4503329.pn.) and (fail\$7 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:40
26	43	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (fail\$7 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:40
27	19	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (fail\$7 near5 induc\$5)	USPAT; US-PGPUB	2004/04/26 16:40
10	1	5475695.pn.	USPAT; US-PGPUB	2004/04/26 17:07
28	0	5475695.pn. and (SEM)	USPAT; US-PGPUB	2004/04/26 17:08
29	0	5475695.pn. and (scanning adj electron adj microscop\$3)	USPAT; US-PGPUB	2004/04/26 17:08
30	3	5475695.pn. or 6320396.pn. or 5523694.pn.	USPAT; US-PGPUB	2004/04/26 17:09
31	1	(5475695.pn. or 6320396.pn. or 5523694.pn.) and DUT	USPAT; US-PGPUB	2004/04/26 17:09
32	1	((5475695.pn. or 6320396.pn. or 5523694.pn.) and DUT) and (induc\$4 near3 (fault\$3 or defect\$3))	USPAT; US-PGPUB	2004/04/26 17:12
33	1	(5475695.pn. or 6320396.pn. or 5523694.pn.) and (image with subtract\$5)	USPAT; US-PGPUB	2004/04/26 17:15
34	60	(5475695.pn. or 6320396.pn. or 5523694.pn.) or (4761607.pn. or 4357540.pn. or 4503329.pn.) or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or 5475695.pn. and (continuous near3 loop\$3)	USPAT; US-PGPUB	2004/04/26 17:18
35	0	((5475695.pn. or 6320396.pn. or 5523694.pn.) and DUT) and (continuous near3 loop\$3)	USPAT; US-PGPUB	2004/04/26 17:16
36	0	(5475695.pn. or 6320396.pn. or 5523694.pn.) and (continuous near3 loop\$3)	USPAT; US-PGPUB	2004/04/26 17:16
37	0	(4761607.pn. or 4357540.pn. or 4503329.pn.) and (continuous near3 loop\$3)	USPAT; US-PGPUB	2004/04/26 17:17
38	0	((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)) and (continuous near3 loop\$3)	USPAT; US-PGPUB	2004/04/26 17:17
39	0	(5475695.pn. or 6320396.pn. or 5523694.pn.) and (continuous near3 loop\$3)	USPAT; US-PGPUB	2004/04/26 17:17

40	0	5475695.pn. and (continuous near3 loop\$3)	USPAT; US-PGPUB	2004/04/26 17:17
41	0	((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)) and (continuous near3 loop\$3)	USPAT; US-PGPUB	2004/04/26 17:18
42	0	((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) and (continuous near3 loop\$3)	USPAT; US-PGPUB	2004/04/26 17:18
43	0	((5475695.pn. or 6320396.pn. or 5523694.pn.) or (4761607.pn. or 4357540.pn. or 4503329.pn.) or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or 5475695.pn.) and (continuous near3 loop\$3)	USPAT; US-PGPUB	2004/04/26 17:18
44	0	((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) and (continuous adj loop\$3)	USPAT; US-PGPUB	2004/04/26 17:19
45	0	(5475695.pn. or 6320396.pn. or 5523694.pn.) and (continuous adj loop\$3)	USPAT; US-PGPUB	2004/04/26 17:19
46	0	(5475695.pn. or 6320396.pn. or 5523694.pn.) and (feedback adj loop\$3)	USPAT; US-PGPUB	2004/04/26 17:19
47	0	5475695.pn. and (feedback adj loop\$3)	USPAT; US-PGPUB	2004/04/26 17:19
48	0	5475695.pn. and (automatic near4 loop\$3)	USPAT; US-PGPUB	2004/04/26 17:20
49	0	5475695.pn. and (automat\$4 near4 loop\$3)	USPAT; US-PGPUB	2004/04/26 17:20
50	1	5475695.pn. and (automat\$4)	USPAT; US-PGPUB	2004/04/26 17:20
51	0	5475695.pn. and (automat\$4 with feedback\$2)	USPAT; US-PGPUB	2004/04/26 17:21
52	0	((5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with induc\$5)) and (automat\$4 with feedback\$2)	USPAT; US-PGPUB	2004/04/26 17:21
54	0	((5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with induc\$5)) and ((automat\$4 or feedback\$2) with loop\$3)	USPAT; US-PGPUB	2004/04/26 17:21
53	24	((5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with induc\$5)) and (automat\$4 or feedback\$2)	USPAT; US-PGPUB	2004/04/26 17:21
55	1	6344750.pn.	USPAT; US-PGPUB	2004/04/26 18:31
56	1	20020043628.pn.	USPAT; US-PGPUB	2004/04/26 18:31

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments
1	BRS	L1	3	4761607.pn. or 4357540.pn. or 4503329.pn.	USPA T; US-P GPUB	2004/04/2 6 16:39	
2	BRS	L2	0	L1 and (until near3 failure)	USPA T; US-P GPUB	2004/04/2 6 16:19	
3	BRS	L3	1	L1 and failure\$2	USPA T; US-P GPUB	2004/04/2 6 16:06	
4	BRS	L4	0	L1 and (failure\$2 with induce\$2)	USPA T; US-P GPUB	2004/04/2 6 16:07	
5	BRS	L5	0	L1 and (failure\$2 with (induc\$5 or introduc\$5))	USPA T; US-P GPUB	2004/04/2 6 16:39	
6	BRS	L6	56	(inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))	USPA T; US-P GPUB	2004/04/2 6 16:08	
7	BRS	L7	15	(inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))	USPA T; US-P GPUB	2004/04/2 6 16:33	
8	BRS	L8	11	(inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)	USPA T; US-P GPUB	2004/04/2 6 16:32	
9	BRS	L9	1	L8 and ((scanning adj electron adj microscop\$5) or SEM)	USPA T; US-P GPUB	2004/04/2 6 16:11	
10	BRS	L10	1	5475695.pn.	USPA T; US-P GPUB	2004/04/2 6 16:17	
11	BRS	L11	0	L10 and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))	USPA T; US-P GPUB	2004/04/2 6 16:18	

	Error Definition	Er ro rs
1		0
2		0
3		0
4		0
5		0
6		0
7		0
8		0
9		0
10		0
11		0

	Type	L #	Hits	Search T xt	DBs	Time Stamp	Comments
12	BRS	L12	0	L10 and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)	USPA T; US-P GPUB	2004/04/26 16:18	
13	BRS	L13	0	L10 and (failure\$2 with induc\$5)	USPA T; US-P GPUB	2004/04/26 16:31	
14	BRS	L14	0	L10 and (until near3 failure)	USPA T; US-P GPUB	2004/04/26 16:30	
15	BRS	L15	1	(L10 or L6 or L1) and (until near3 failure)	USPA T; US-P GPUB	2004/04/26 16:30	
16	BRS	L17	11	(L10 or L6 or L1) and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)	USPA T; US-P GPUB	2004/04/26 16:32	
17	BRS	L18	15	(L10 or L6 or L1) and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))	USPA T; US-P GPUB	2004/04/26 16:32	
18	BRS	L19	15	L7 not L11	USPA T; US-P GPUB	2004/04/26 16:33	
19	BRS	L20	4	L7 not L8	USPA T; US-P GPUB	2004/04/26 16:33	
20	BRS	L16	43	(L10 or L6 or L1) and (failure\$2 with induc\$5)	USPA T; US-P GPUB	2004/04/26 16:37	
21	BRS	L21	0	(L10 or L6 or L1) and (failure\$2 with induc\$5 with (maximum near3 rating))	USPA T; US-P GPUB	2004/04/26 16:38	
22	BRS	L22	0	(L10 or L6 or L1) and (failure\$2 with (maximum near3 rating))	USPA T; US-P GPUB	2004/04/26 16:38	

	Error Definition	Er ro rs
12		0
13		0
14		0
15		0
16		0
17		0
18		0
19		0
20		0
21		0
22		0

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments
23	BRS	L23	0	(L10 or L6 or L1) and failure\$2 and (maximum near3 rating)	USPA T; US-P GPUB	2004/04/26 16:39	
24	BRS	L24	0	L1 and (failure\$2 with induc\$5)	USPA T; US-P GPUB	2004/04/26 16:39	
25	BRS	L25	0	L1 and (fail\$7 with induc\$5)	USPA T; US-P GPUB	2004/04/26 16:40	
26	BRS	L26	43	(L10 or L6 or L1) and (fail\$7 with induc\$5)	USPA T; US-P GPUB	2004/04/26 16:40	
27	BRS	L27	19	(L10 or L6 or L1) and (fail\$7 near5 induc\$5)	USPA T; US-P GPUB	2004/04/26 16:40	

	Error Definition	Er ro rs
23		0
24		0
25		0
26		0
27		0

L Number	Hits	Search Text	DB	Time stamp
1	3	4761607.pn. or 4357540.pn. or 4503329.pn.	USPAT; US-PGPUB	2004/04/26 16:39
2	0	(4761607.pn. or 4357540.pn. or 4503329.pn.) and (until near3 failure)	USPAT; US-PGPUB	2004/04/26 16:19
3	1	(4761607.pn. or 4357540.pn. or 4503329.pn.) and failure\$2	USPAT; US-PGPUB	2004/04/26 16:06
4	0	(4761607.pn. or 4357540.pn. or 4503329.pn.) and (failure\$2 with induce\$2)	USPAT; US-PGPUB	2004/04/26 16:07
5	0	(4761607.pn. or 4357540.pn. or 4503329.pn.) and (failure\$2 with (induc\$5 or introduc\$5))	USPAT; US-PGPUB	2004/04/26 16:39
6	56	(inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))	USPAT; US-PGPUB	2004/04/26 16:08
7	15	(inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))	USPAT; US-PGPUB	2004/04/26 16:33
8	11	(inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:32
9	1	((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)) and ((scanning adj electron adj microscop\$5) or SEM)	USPAT; US-PGPUB	2004/04/26 16:11
10	1	5475695.pn.	USPAT; US-PGPUB	2004/04/26 16:17
11	0	5475695.pn. and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))	USPAT; US-PGPUB	2004/04/26 16:18
12	0	5475695.pn. and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:18
13	0	5475695.pn. and (failure\$2 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:31
14	0	5475695.pn. and (until near3 failure)	USPAT; US-PGPUB	2004/04/26 16:30
15	1	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (until near3 failure)	USPAT; US-PGPUB	2004/04/26 16:30
17	11	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:32
18	15	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))	USPAT; US-PGPUB	2004/04/26 16:32
19	15	((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))) not (5475695.pn. and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5)))	USPAT; US-PGPUB	2004/04/26 16:33
20	4	((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))) not ((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5))	USPAT; US-PGPUB	2004/04/26 16:33

16	43	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:37
21	0	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with induc\$5 with (maximum near3 rating))	USPAT; US-PGPUB	2004/04/26 16:38
22	0	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with (maximum near3 rating))	USPAT; US-PGPUB	2004/04/26 16:38
23	0	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and failure\$2 and (maximum near3 rating)	USPAT; US-PGPUB	2004/04/26 16:39
24	0	(4761607.pn. or 4357540.pn. or 4503329.pn.) and (failure\$2 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:39
25	0	(4761607.pn. or 4357540.pn. or 4503329.pn.) and (fail\$7 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:40
26	43	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (fail\$7 with induc\$5)	USPAT; US-PGPUB	2004/04/26 16:40
27	19	(5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (fail\$7 near5 induc\$5)	USPAT; US-PGPUB	2004/04/26 16:40